

Application/Control No.	Applicant(s)/Paten Reexamination	under
10/023,455	OHNISHI ET AL.	
Examiner	Art Unit	
Jan M. Ludlow	1743	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
updated search	4/17/2006	, JML